

FORM PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)	Docket Number (Optional)	Application Number
	40030043-02	Not yet assigned
	Applicant	
	Iwaskai et al.	
	Filing Date	Group Art Unit
	herewith	Not yet assigned

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, Etc.)

MK	Hewlett-Packard Co., "HP4072A Advanced Parametric Tester with HP SPECS," Published in 1999.
MK	Agilent Technologies, Inc., "Agilent 4070 Series Accurate Capacitance Characterization at the Water Level," Application Note 4070-2, Published in 2000.
MK	Meiko Matsumura et al., "Negative-Capacitance Effect in Forward-Biased Metal Oxide Semiconductor Tunnel Diodes (MOSTD)," Japan, Vol. 39 (2000), pp. L123-L125, Part 2, No. 2B, February 15, 2000.

EXAMINER <i>M. Iwaskai</i>	DATE CONSIDERED <i>3/30/05</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP §609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.